

Amendments to the Specification

In the Abstract, please amend the following.

~~A test module for testing the susceptibility of an integrated circuit design to latch-up, the test module comprising a plurality of test blocks (30), connected in parallel, each test block (30) comprising an injector block (12) for applying a stress current or voltage to the respective test block (30), and a plurality of sensor blocks (13) located at successively increasing distances from the respective injector block (12), each sensor block (13) comprising a PNPN latch-up test structure. The present invention combines the respective advantages of conventional IC stress current testing and latch-up parameter measurement using a standard PNPN latch-up test structure.~~

In an example embodiment, there is a test module for testing the susceptibility of an integrated circuit design to latch-up. The test module comprises a plurality of test blocks, connected in parallel. Each test block includes an injector block for applying a stress current or voltage to the respective test block and a plurality of sensor blocks located at successively increasing distances from the respective injector block. Each sensor block includes a PNPN latch-up test structure. The present invention combines the respective advantages of IC stress current testing and latch-up parameter measurement using a standard PNPN latch-up test structure.